

<b>Notice of References Cited</b>	Application/Control No. 09/761,640	Applicant(s)/Patent Under Reexamination WEI ET AL.	
	Examiner Quang Nguyen, Ph.D.	Art Unit 1636	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,825,021 B2	11-2004	Luche et al.	435/196
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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